

Search Notes

Application/Control No.

10/544,253

Examiner

HUYEN D. LE

Applicant(s)/Patent under
Reexamination

OHBAYASHI ET AL.

Art Unit

2615

SEARCHED

Class	Subclass	Date	Examiner
381	113, 116, 174, 175, 190, 191	3/27/2007	HL
381	369		HL
367	170		HL
367	181		HL
367	140		HL
310	322		HL
310	334		HL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner